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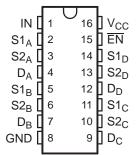
SCDS164D-MAY 2004-REVISED JUNE 2009

QUAD SPDT WIDE-BANDWIDTH VIDEO SWITCH WITH LOW ON-STATE RESISTANCE

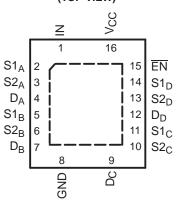
FEATURES

- Low Differential Gain and Phase (D_G = 0.64%, D_P = 0.1 Degrees Typ)
- Wide Bandwidth (BW = 300 MHz Min)
- Low Crosstalk (X_{TALK} = -63 dB Typ)
- Low Power Consumption (I_{CC} = 3 μA Max)
- Bidirectional Data Flow With Near-Zero Propagation Delay
- Low ON-State Resistance (r_{on} = 3 Ω Typ)
- V_{CC} Operating Range From 4.5 V to 5.5 V
- I_{off} Supports Partial-Power-Down Mode Operation
- Data and Control Inputs Provide Undershoot Clamp Diode
- Control Inputs Can Be Driven by TTL or 5-V/3.3-V CMOS Outputs
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Performance Tested Per JESD 22
 - 1000-V Charged-Device Model (C101)
- Suitable for Both RGB and Composite-Video Switching

D, DBQ, OR PW PACKAGE (TOP VIEW)



RGY PACKAGE (TOP VIEW)



DESCRIPTION/ORDERING INFORMATION

The TS5V330 video switch is a 4-bit 1-of-2 multiplexer/demultiplexer with a single switch-enable (\overline{EN}) input. When \overline{EN} is low, the switch is enabled and the D port is connected to the S port. When \overline{EN} is high, the switch is disabled and the high-impedance state exists between the D and S ports. The select (IN) input controls the data path of the multiplexer/demultiplexer.

Low differential gain and phase make this switch ideal for composite and RGB video applications. This device has wide bandwidth and low crosstalk, making it suitable for high-frequency applications as well.

This device is fully specified for partial-power-down applications using loff. The loff feature ensures that damaging current will not backflow through the device when it is powered down. This switch maintains isolation during power off.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



ORDERING INFORMATION

T _A	PACKAGE ⁽¹⁾		ORDERABLE PART NUMBER	TOP-SIDE MARKING
	QFN – RGY	Tape and reel	TS5V330RGYR	TE330
–40°C to 85°C	SOIC – D	Tube	TS5V330D	TS5V330
	201C - D	Tape and reel	TS5V330DR	1307330
	SSOP (QSOP) – DBQ	Tape and reel	TS5V330DBQR	TE330
	TSSOP – PW	Tube	TS5V330PW	TF220
	1330F - FW	Tape and reel	TS5V330PWR	TE330

⁽¹⁾ Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

DESCRIPTION/ORDERING INFORMATION (CONTINUED)

To ensure the high-impedance state during power up or power down, $\overline{\text{EN}}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

FUNCTION TABLE

INP	INPUTS INPUT/OUTPUT		FUNCTION		
EN	IN	D	FUNCTION		
L	L	S1	D port = S1 port		
L	Н	S2	D port = S2 port		
Н	Χ	Z	Disconnect		

PIN DESCRIPTION

PIN	DESCRIPTION	
S1, S2	Analog video I/Os	
D	Analog video I/Os	
IN	Select input	
ĒN	Switch-enable input	

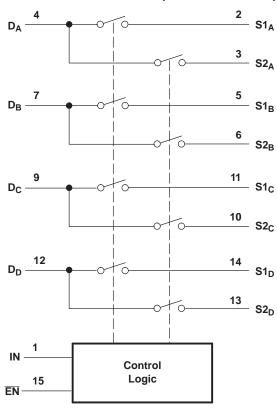
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PARAMETER DEFINITIONS

PARAMETER	DESCRIPTION
r _{on}	Resistance between the D and S ports, with the switch in the ON state
I _{OZ}	Output leakage current measured at the D and S ports, with the switch in the OFF state
Ios	Short-circuit current measured at the I/O pins
V _{IN}	Voltage at IN
V _{EN}	Voltage at EN
C _{IN}	Capacitance at the control (EN, IN) inputs
C_{OFF}	Capacitance at the analog I/O port when the switch is OFF
C _{ON}	Capacitance at the analog I/O port when the switch is ON
V _{IH}	Minimum input voltage for logic high for the control (EN, IN) inputs
V _{IL}	Minimum input voltage for logic low for the control (EN, IN) inputs
V_{hys}	Hysteresis voltage at the control (EN, IN) inputs
V _{IK}	I/O and control (EN, IN) inputs diode clamp voltage
VI	Voltage applied to the D or S pins when D or S is the switch input
Vo	Voltage applied to the D or S pins when D or S is the switch output
I _{IH}	Input high leakage current of the control (EN, IN) inputs
I _{IL}	Input low leakage current of the control (EN, IN) inputs
I _I	Current into the D or S pins when D or S is the switch input
Io	Current into the D or S pins when D or S is the switch output
I _{off}	Output leakage current measured at the D or S ports, with $V_{CC} = 0$
t _{ON}	Propagation delay measured between 50% of the digital input to 90% of the analog output when switch is turned ON
t _{OFF}	Propagation delay measured between 50% of the digital input to 90% of the analog output when switch is turned OFF
BW	Frequency response of the switch in the ON state measured at –3 dB
X _{TALK}	Unwanted signal coupled from channel to channel. Measured in $-dB$. $X_{TALK} = 20 \log V_O/V_I$. This is a nonadjacent crosstalk.
O_{IRR}	Off isolation is the resistance (measured in –dB) between the input and output with the switch OFF.
D_G	Magnitude variation between analog input and output pins when the switch is ON and the dc offset of composite-video signal varies at the analog input pin. In the NTSC standard, the frequency of the video signal is 3.58 MHz, and dc offset is from 0 to 0.714 V.
D _P	Phase variation between analog input and output pins when the switch is ON and the dc offset of composite-video signal varies at the analog input pin. In the NTSC standard, the frequency of the video signal is 3.58 MHz, and dc offset is from 0 to 0.714 V.
I _{CC}	Static power-supply current
I _{CCD}	Variation of I _{CC} for a change in frequency in the control (EN, IN) inputs
Δl _{CC}	This is the increase in supply current for each control input that is at the specified voltage level, rather than V _{CC} or GND.



FUNCTIONAL DIAGRAM (POSITIVE LOGIC)



Absolute Maximum Ratings(1)

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V_{CC}	Supply voltage range		-0.5	7	V
V_{IN}	Control input voltage range (2)(3)			7	V
V _{I/O}	O Switch I/O voltage range ⁽²⁾⁽³⁾⁽⁴⁾		-0.5	7	V
I _{IK}	Control input clamp current	V _{IN} < 0		- 50	mA
I _{I/OK}	I/O port clamp current	V _{I/O} < 0		-50	mA
I _{I/O}	ON-state switch current ⁽⁵⁾			±128	mA
	Continuous current through V _{CC} or GND			±100	mA
		D package ⁽⁶⁾		73	
0		DBQ package ⁽⁶⁾		90	
θ_{JA}	Package thermal impedance	PW package ⁽⁶⁾		108	°C/W
		RGY package ⁽⁷⁾		39	
T _{stg}	Storage temperature range		-65	150	°C

- Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- All voltages are with respect to ground, unless otherwise specified.
- The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
- V_I and V_O are used to denote specific conditions for V_{I/O}.
- $I_{\rm I}$ and $I_{\rm O}$ are used to denote specific conditions for $I_{\rm I/O}$. The package thermal impedance is calculated in accordance with JESD 51-7.
- The package thermal impedance is calculated in accordance with JESD 51-5.

Submit Documentation Feedback

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Recommended Operating Conditions⁽¹⁾

		MIN	MAX	UNIT
V _{CC}	Supply voltage range	4	5.5	V
V _{IH}	High-level control input voltage range (EN, IN)	2	5.5	V
V _{IL}	Low-level control input voltage range (EN, IN)	0	0.8	V
V _{ANALOG}	Analog I/O voltage range	0	Vcc	V
T _A	Operating free-air temperature range	-40	85	ç

All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

Electrical Characteristics

over recommended operating free-air temperature range, $V_{CC} = 5 \text{ V} \pm 10\%$ (unless otherwise noted)

PARA	AMETER		TEST CONDITIONS ⁽¹⁾			MIN	TYP ⁽²⁾	MAX	UNIT
V_{IK}	EN, IN	$V_{CC} = 4.5 \text{ V},$	I _{IN} = -18 mA					-1.8	V
V_{hys}	EN, IN						150		mV
I _{IH}	EN, IN	$V_{CC} = 5.5 V,$	V_{IN} and $V_{EN} = V_{CC}$					±1	μΑ
I_{IL}	EN, IN	$V_{CC} = 5.5 V,$	V_{IN} and $V_{EN} = GND$					±1	μΑ
$I_{OZ}^{(3)}$		$V_{CC} = 5.5 V,$	$V_0 = 0 \text{ to } 5.5 \text{ V},$	$V_I = 0$,	Switch OFF			±1	μΑ
I _{OS} (4)		$V_{CC} = 5.5 V,$	$V_{O} = 0.5 V_{CC,}$	$V_{I} = 0,$	Switch ON	50			mA
$I_{\rm off}$		$V_{CC} = 0 V$,	$V_0 = 0 \text{ to } 5.5 \text{ V},$	$V_I = 0$				1	μΑ
Icc		$V_{CC} = 5.5 V,$	$I_{I/O} = 0$,	Switch ON or OFF				3	μΑ
ΔI_{CC}	EN, IN	$V_{CC} = 5.5 V,$	One input at 3.4 V,	Other inputs at V _{CC}	or GND			2.5	mA
I_{CCD}		V _{EN} = GND, V	$t_{CC} = 5.5 \text{ V}, D \text{ and S p}$	orts open, V _{IN} input	switching 50% duty cycle			0.25	mA/MHz
C _{IN}	ĒN, IN	V_{IN} of $V_{EN} = 0$ f = 1 MHz	,				3.5		pF
C	D port	V - 0	f = 1 MHz,	Outpute open	Switch OFF		6		pF
C _{OFF}	S port	$V_I = 0$,	i = i ivi⊓z,	Outputs open,	SWILCH OFF		4		рг
C_{ON}		$V_I = 0$,	f = 1 MHz,	Outputs open,	Switch ON		14		pF
r _{on} (5)		V _{CC} = 4.5 V	$V_I = 1 V$,	$I_{O} = 13 \text{ mA},$	$R_L = 75 \Omega$		3	7	Ω
on`′		v _{CC} = 4.5 v	V _I = 2 V,	$I_O = 26 \text{ mA},$	$R_L = 75 \Omega$		7	10	22

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⁽¹⁾ V_I, V_O, I_I, and I_O refer to I/O pins.
(2) All typical values are at V_{CC} = 5 V (unless otherwise noted), T_A = 25°C.
(3) For I/O ports, I_{OZ} includes the input leakage current.
(4) The I_{OS} test is applicable to only one ON channel at a time. The duration of this test is less than 1 s.
(5) Measurement by the voltage drop between the D and S terminals at the indicated current through the switch. ON-state resistance is determined by the lower of the voltages of the two (D or S) terminals.



Switching Characteristics

over recommended operating free-air temperature range, V_{CC} = 5 V ± 10%, R_L = 75 Ω , C_L = 20 pF (unless otherwise noted) (see Figure 5)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYP	MAX	UNIT
t _{ON}	S	D		2.5	6	ns
t _{OFF}	S	D		1.1	6	ns

Dynamic Characteristics

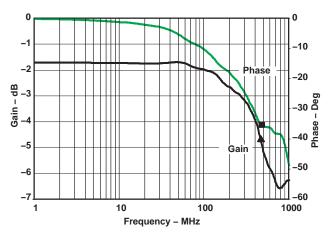
over recommended operating free-air temperature range, V_{CC} = 5 V \pm 10% (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP ⁽¹⁾	MAX	UNIT
D _G ⁽²⁾	$R_L = 150 \Omega$,	f = 3.58 MHz,	See Figure 6			0.64		%
D _P ⁽²⁾	$R_L = 150 \Omega$,	f = 3.58 MHz,	See Figure 6			0.1		Deg
BW	$R_L = 150 \Omega$,	See Figure 7			300			MHz
X _{TALK}	$R_L = 150 \Omega$,	f = 10 MHz,	RIN = 10 Ω,	See Figure 8		-63		dB
O _{IRR}	$R_L = 150 \Omega$,	f = 10 MHz,	See Figure 9			-60		dB

⁽¹⁾ All typical values are at V_{CC} = 5 V (unless otherwise noted), T_A = 25°C. (2) D_G and D_P are expressed in absolute magnitude.

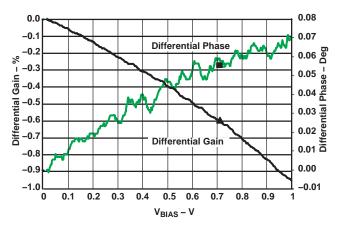


OPERATING CHARACTERISTICS



- Phase at -3-dB Frequency, 35 Degrees
- ▲ Gain –3 dB at 460 MHz

Figure 1. Gain/Phase vs Frequency



- Differential Phase at 0.714, 0.056 Degrees
- ▲ Differential Gain at 0.714, -0.63%

Figure 2. Differential Gain/Phase vs V_{BIAS}



OPERATING CHARACTERISTICS

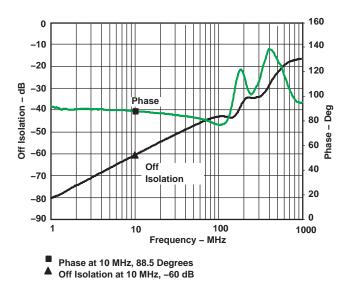
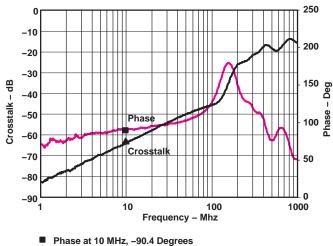


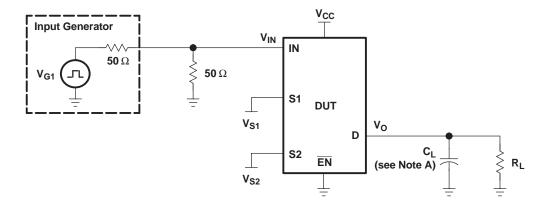
Figure 3. Off Isolation vs Frequency



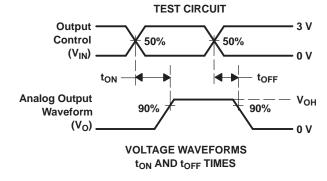
Phase at 10 MHz, -90.4 Degrees Crosstalk at 10 MHz, -63.9 dB

Figure 4. Crosstalk vs Frequency





TEST	V _{CC}	R _L	CL	V _{S1}	V _{S2}
t _{ON}	$\begin{array}{c} \textbf{5 V} \pm \textbf{0.5 V} \\ \textbf{5 V} \pm \textbf{0.5 V} \end{array}$	75 75	20 20	GND 3 V	3 V GND
t _{OFF}	$\begin{array}{c} \textbf{5 V} \pm \textbf{0.5 V} \\ \textbf{5 V} \pm \textbf{0.5 V} \end{array}$	75 75	20 20	GND 3 V	3 V GND

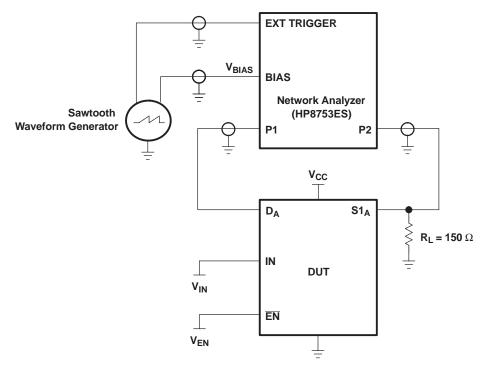


NOTES: A. C_L includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_0 = 50 \Omega$, $t_r \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- C. The outputs are measured one at a time, with one transition per measurement.

Figure 5. Test Circuit and Voltage Waveforms





NOTE A: For additional information on measurement method, refer to the TI application report, *Measuring Differential Gain and Phase*, literature number SLOA040.

Figure 6. Test Circuit for Differential Gain/Phase Measurement

Differential gain and phase are measured at the output of the ON channel. For example, when $V_{IN} = 0$, $V_{EN} = 0$, and DA is the input, the output is measured at S1_A.

HP8753ES Setup

Average = 20
RBW = 300 Hz
ST = 1.381 s
P1 = -7 dBM
CW frequency = 3.58 MHz

Sawtooth Waveform Generator Setup

 $V_{BIAS} = 0$ to 1 V Frequency = 0.905 Hz



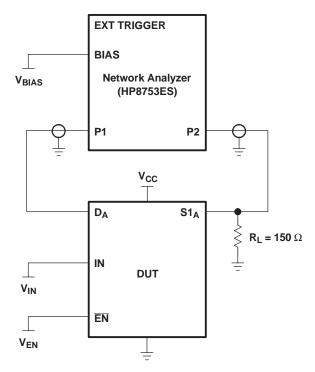


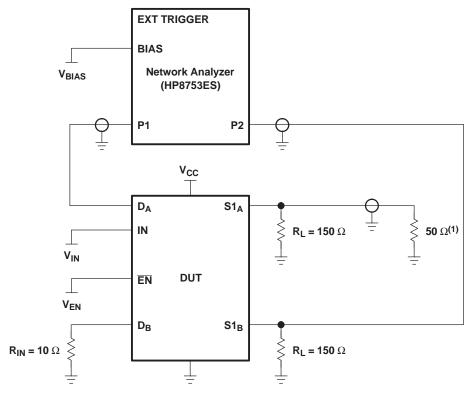
Figure 7. Test Circuit for Frequency Response (BW)

Frequency response is measured at the output of the ON channel. For example, when $V_{IN}=0$, $V_{EN}=0$, and D_A is the input, the output is measured at S1_A. All unused analog I/O ports are left open.

HP8753ES Setup

Average = 4 RBW = 3 Hz V _{BIAS} = 0.35 V	
ST = 2 s	
P1 = 0 dBM	





(1) A 50- Ω termination resistor is needed for the network analyzer.

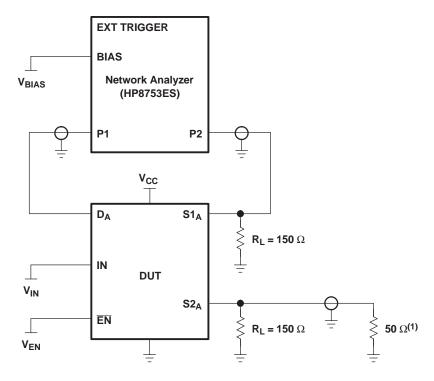
Figure 8. Test Circuit for Crosstalk (X_{TALK})

Crosstalk is measured at the output of the nonadjacent ON channel. For example, when $V_{IN} = 0$, $V_{EN} = 0$, and D_A is the input, the output is measured at S1_B. All unused analog input (D) ports and output (S) ports are connected to GND through 10- Ω and 50- Ω pulldown resistors, respectively.

HP8753ES Setup

Average = 4 RBW = 3 kHz	
$V_{BIAS} = 0.35 \text{ V}$	
ST = 2 s	
P1 = 0 dBM	





(1) A 50- Ω termination resistor is needed for the network analyzer.

Figure 9. Test Circuit for Off Isolation (OIRR)

Off isolation is measured at the output of the OFF channel. For example, when $V_{IN} = V_{CC}$, $V_{EN} = 0$, and D_A is the input, the output is measured at S1_A. All unused analog input (D) ports are left open, and output (S) ports are connected to GND through $50-\Omega$ pulldown resistors.

HP8753ES Setup

Average = 4
RBW = 3 kHz
V_{BIAS} = 0.35 V
ST = 2 s
P1 = 0 dBM

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24-Aug-2018

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing		Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TS5V330D	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	TS5V330	Samples
TS5V330DBQR	ACTIVE	SSOP	DBQ	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	TE330	Samples
TS5V330DBQRG4	ACTIVE	SSOP	DBQ	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	TE330	Samples
TS5V330DR	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	TS5V330	Samples
TS5V330PW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	TE330	Samples
TS5V330PWG4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	TE330	Samples
TS5V330PWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	TE330	Samples
TS5V330RGYR	ACTIVE	VQFN	RGY	16	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	TE330	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.



PACKAGE OPTION ADDENDUM

24-Aug-2018

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TS5V330DBQR	SSOP	DBQ	16	2500	330.0	12.5	6.4	5.2	2.1	8.0	12.0	Q1
TS5V330DR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
TS5V330PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
TS5V330RGYR	VQFN	RGY	16	3000	330.0	12.4	3.8	4.3	1.5	8.0	12.0	Q1

www.ti.com 18-Oct-2016



*All dimensions are nominal

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Device	Package Type	Package Drawing	Pins SPQ		Length (mm)	Width (mm)	Height (mm)
TS5V330DBQR	SSOP	DBQ	16	2500	340.5	338.1	20.6
TS5V330DR	SOIC	D	16	2500	333.2	345.9	28.6
TS5V330PWR	TSSOP	PW	16	2000	367.0	367.0	35.0
TS5V330RGYR	VQFN	RGY	16	3000	367.0	367.0	35.0



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.







- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 inch, per side.
- 4. This dimension does not include interlead flash.5. Reference JEDEC registration MO-137, variation AB.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. QFN (Quad Flatpack No-Lead) package configuration.
- D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
- Pin 1 identifiers are located on both top and bottom of the package and within the zone indicated. The Pin 1 identifiers are either a molded, marked, or metal feature.
- G. Package complies to JEDEC MO-241 variation BA.



RGY (R-PVQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View

Exposed Thermal Pad Dimensions

4206353-3/P 03/14

NOTE: All linear dimensions are in millimeters



RGY (R-PVQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat—Pack QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com http://www.ti.com.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.



D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.





SMALL OUTLINE PACKAGE



- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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